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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/082,211	ONISHI ET AL.	
Examiner	Art Unit	
Karin M. Reichle	3761	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			
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(INCLUDING SEARCH	TES STRATEGY)
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updated Inventor name search in eDAN and EAST search-copies attached	6/15/2005	KMR
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